



Docket No.: H6808.0039/P039  
(PATENT)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

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In re Patent Application of:  
Yuuki Ojima et al.

Application No.: 10/779,848

Confirmation No.: 9446

Filed: February 18, 2004

Art Unit: 2881

For: SCANNING ELECTRON MICROSCOPE  
\_\_\_\_\_  
WITH MEASUREMENT FUNCTION

Examiner: J. L. Smith

**AMENDMENT IN RESPONSE TO NON-FINAL OFFICE ACTION**

MS Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

**INTRODUCTORY COMMENTS**

In response to the Office Action dated May 3, 2005, please amend the above-identified U.S. patent application as follows:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 4 of this paper.